Notice of References Cited Application/Control No. 10/621,030 Applicant(s)/Patent Under Reexamination KIRSCH ET AL. Examiner SIMON D. NGUYEN Applicant(s)/Patent Under Reexamination KIRSCH ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,731,911	05-2004	Hirata et al.	455/71
*	В	US-6,639,939	10-2003	Naden et al.	375/140
*	С	US-5,594,754	01-1997	Dohi et al.	375/148
*	D	US-2003/0114110	06-2003	Dahlback et al.	455/67.1
*	Е	US-6,289,061	09-2001	Kandala et al.	375/344
*	F	US-2002/0177458	11-2002	Hokao, Tomoaki	455/502
*	G	US-6,933,788	08-2005	Forrester, Tim	331/1R
*	Н	US-6,704,555	03-2004	Sih et al.	455/245.1
*	1	US-6,704,552	03-2004	Matsumoto, Mariko	455/164.1
*	J	US-6,571,088	05-2003	Hasegawa, Osamu	455/182.2
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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